Session 3C— IP Session: Nanometer IC Testing: Perspectives from Foundries

Organizer: Cheng-Wen Wu, National Tsing Hua University

In nanometer IC manufacturing, testing plays an even more important role than ever. The concern is no longer just defect screening and test coverage, but also reliability and yield. We have three speakers representing three major IC foundries, respectively. They will talk about the challenges they have seen from past experiences, and give directions of the trend regarding test practices, including failure/defect analysis and diagnosis, yield enhancement, DFT, etc.

Presentations:

Yield, Whose Responsibility Is It?
Cheng-Ju Hsieh, Faraday Technology Corp. (A subsidiary of UMC)

Nanometer IC Testing — Perspectives from Chartered
Chafik Behidj, Chartered Semiconductor

Nanometer IC Testing — Perspectives from TSMC
Ann Luh, TSMC Test Division